



Docket No.: M4065.0215/P215
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Eugene A. DeLaRosa et al.

Application No.: 09/516,581

Confirmation No.: 3124

Filed: March 1, 2000

Art Unit: 2621

For: METHOD FOR MEASURING
REGISTRATION OF OVERLAPPING
MATERIAL LAYERS OF AN INTEGRATED
CIRCUIT

Examiner: B. P. Werner

Do Not
Enter
12/23/05

AMENDMENT AFTER FINAL ACTION (37 C.F.R. SECTION 1.116)

MS AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Entered
w/ICE
1-17-06
PRUWER
2-8-06

Dear Sir:

INTRODUCTORY COMMENTS

In response to the Office Action dated September 15, 2005, finally rejecting claims 1, 3-14, 16-27, and 29-39, please amend the above-identified U.S. patent application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 9 of this paper.